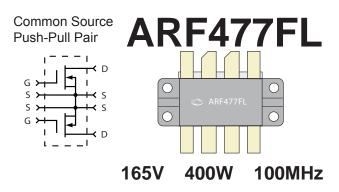


RF POWER MOSFET

N-CHANNEL PUSH - PULL PAIR



The ARF477FL is a matched pair of RF power transistors in a common source configuration. It is designed for high voltage push-pull or parallel operation in narrow band ISM and MRI power amplifiers up to 100 MHz.

• Specified 150 Volt, 65 MHz Characteristics:

Output Power = 400 Watts

Gain = 15dB (Class AB)

Efficiency = 50% min

- High Performance Push-Pull RF Package.
- High Voltage Breakdown and Large SOA for Superior Ruggedness.
- Low Thermal Resistance.
- RoHS Compliant

MAXIMUM RATINGS

All Ratings: $T_{C} = 25^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Ratings	Unit	
V _{DSS}	Drain-Source Voltage	500	V	
V _{DGO}	Drain-Gate Voltage	500	v	
Ι _D	Continuous Drain Current @ T _c = 25°C (each device)	15	А	
V _{GS}	Gate-Source Voltage	±30	V	
P _D	Total Power Dissipation @ $T_c = 25^{\circ}C$	750	W	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 to 175	°C	
TL	Lead Temperature: 0.063" from Case for 10 Sec.	300		

Static Electrical Characteristics

Symbol	Parameter		Тур	Max	Unit
BV _{DSS}	Drain-Source Breakdown Voltage (V_{GS} = 0V, I_{D} = 250 µA)	500			V
V _{DS(ON)}	$V_{DS(ON)}$ On State Drain Voltage ¹ ($I_{D(ON)}$ = 7.5A, V_{GS} = 10V)		2.9	4	v
	Zero Gate Voltage Drain Current ($V_{DS} = V_{DSS}$, $V_{GS} = 0V$)			25	
I _{DSS}	Zero Gate Voltage Drain Current ($V_{DS} = 50V_{DSS}$, $V_{GS} = 0$, $T_{C} = 125^{\circ}C$)			250	μA
I _{GSS}	I_{GSS} Gate-Source Leakage Current ($V_{GS} = \pm 30V, V_{DS} = 0V$)			±100	nA
9 _{fs}	g_{fs} Forward Transconductance (V_{DS} = 15V, I_{D} = 7.5A)		5.6	8	mhos
$g_{fs1}^{\prime}/g_{fa2}^{\prime}$	$g_{f_{51}}/g_{f_{52}}$ Forward Transconductance Match Ratio (V_{DS} = 15V, I_{D} = 5A)			1.1	
V _{GS(TH)}	Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_{D} = 50$ mA)	3		5	
V _{GS(TH)}	Gate Threshold Voltage Match ($V_{DS} = V_{GS}$, $I_{D} = 50$ mA)			0.2	Volts

Thermal Characteristics

Syml	bol	Parameter	Min	Тур	Max	Unit
R _{eJ}	с	Junction to Case		0.18	0.2	°C/W
R _{ejt}	IS	Junction to Sink (High Efficiency Thermal Joint Compound and Planar Heat Sink Surface.)		0.30	0.32	C/W

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

DYNAMIC CHARACTERISTICS (per section)

ARF477FL

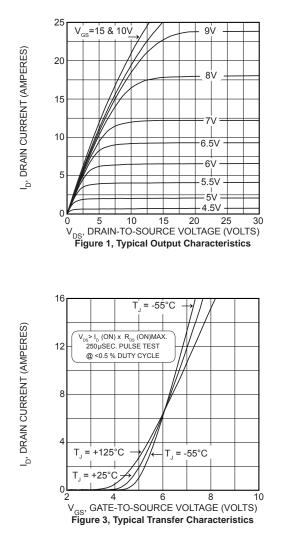
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C _{ISS}	Input Capacitance	V _{GS} = 0V		1200	1400	
C _{oss}	Output Capacitance	V _{DS} = 150V		150	180	pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		60	75	
t _{d(on)}	Turn-on Delay Time	V _{GS} = 15V		7		
t _r	Rise Time	V _{DD} = 250V		6		nS
t _{d(off)}	Turn-off Delay Time	$I_{D} = I_{D[Cont.]} @ 25^{\circ}C$		20		113
t _r	Fall Time	R _G = 1.6 Ω		4.0	7	

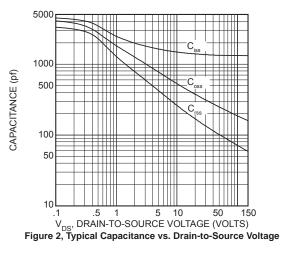
Functional Characteristics

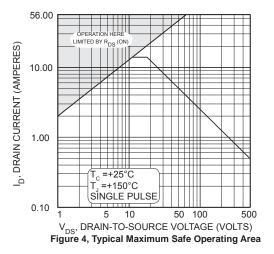
Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
G _{PS}	Common Source Amplifier Power Gain	f = 65MHz	14	16		dB
η	Drain Efficiency	I _{dq} = 0mA V _{DD} = 150V	50	55		%
Ψ	Electrical Ruggedness VSWR 10:1	P _{out} = 400W No Degradation in Output		Output Pov	wer	

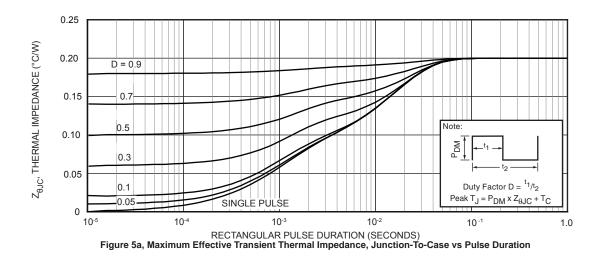
1. Pulse Test: Pulse width < 380 μ S, Duty Cycle < 2%.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.









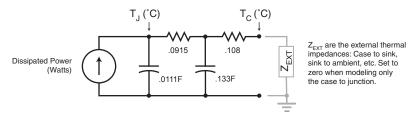
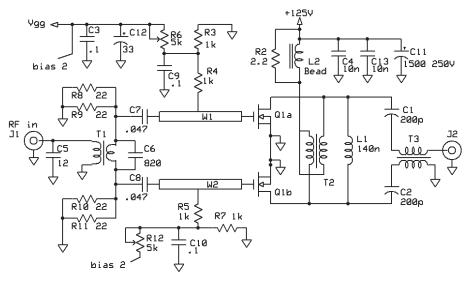


Figure 5b, TRANSIENT THERMAL IMPEDANCE MODEL

Freq. (MHz)	Z _{in} (Ω)	Ζ _{ουτ} (Ω)
40	1.5 - j 10	24 - j 37
60	1.9 - j 1.3	13 - j 29
80	2.2 - j 0.82	7.9 - j 24

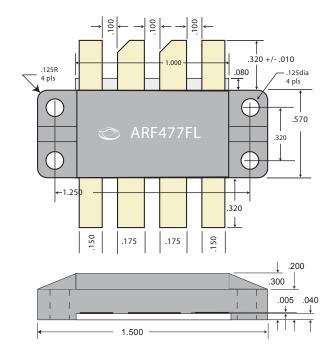
 $\begin{array}{ll} Z_{_{|N}} \mbox{-} Gate \mbox{ shunted with } 100 \Omega & I_{_{dq}} = 0 \\ Z_{_{OL}} \mbox{-} Conjugate \mbox{ of optimum load for } 400 \mbox{ Watts output at } V_{_{dd}} \mbox{=} 125 V \end{array}$

65MHz Test Circuit



- C6 ATC 100B type
- L1 4.5t #18 enam .312"dia
- L2 = 2t #18 on FairRite 2643800302 bead
- R8-R11 22 ohm 1W SMT
- T1= 4:1 2t #20 1t 1.5" braid on 2861001502

T2 = 6t #22 bifilar on FairRite 5961000301 T3 = 2t RG316 on FairRite 2861010002 Qla/b ARF477FL W1, W2 - 1.4" x .2" PWB = FR-4 fiberglass er= 4.6



Thermal Considerations and Package Mounting:

The rated power dissipation is only available when the package mounting surface is at 25°C and the junction temperature is 175°C. The thermal resistance between junctions and case mounting surface is 0.23 °C/W. When installed, an additional thermal impedance of 0.07°C/W between the package base and the mounting surface is typical. Insure that the mounting surface is smooth and flat. Thermal joint compound must be used to reduce the effects of small surface irregularities. Use the minimum amount necessary to coat the surface. The heatsink should incorporate a copper heat spreader to obtain best results.

The package design clamps the ceramic base to the heatsink. A clamped joint maintains the required mounting pressure while allowing for thermal expansion of both the base and the heat sink. Four 4-40 (M3) screws provide the required mounting force. T = 6 in-lb (0.68 N-m).

HAZARDOUS MATERIAL WARNING The white ceramic portion of the device between leads and mounting surface is beryllium oxide, BeO. Beryllium oxide dust is toxic when inhaled. Care must be taken during handling and mounting to avoid damage to this area. These devices must never be thrown away with general industrial or domestic waste.

Microsemi's products are covered by one or more of U.S. patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522 5,262,336 6,503,786 5,256,583 4,748,103 5,283,202 5,231,474 5,434,095 5,528,058 6,939,743 7,352,045 5,283,201 5,801,417 5,648,283 7,196,634 6,664,594 7,157,886 6,939,743 7,342,262 and foreign patents. US and Foreign patents pending. All Rights Reserved.

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